

**ADG811/812 at E\_TSMC1108 (0.35C1P4M33.00) Qualification Data Summary**

| QUALIFICATION PLAN / STATUS                                          |                                 |                         |               |
|----------------------------------------------------------------------|---------------------------------|-------------------------|---------------|
| TEST                                                                 | SPECIFICATION                   | SAMPLE SIZE             | RESULTS       |
| High Temperature Operating Life (HTOL)*                              | JEDEC <i>JESD22-A108</i>        | 2x45<br>7x77            | Pass          |
| Highly Accelerated Stress Test (HAST)*                               | JEDEC <i>JESD22-A110</i>        | 4x77<br>5x45            | Pass          |
| ELF                                                                  | MIL-STD-883, <i>Method 1015</i> | 3x667<br>3x667<br>3x667 | Pass          |
| High Temperature Storage Life (HTSL)                                 | JEDEC <i>JESD22-A103</i>        | 1x77<br>3x45            | Pass          |
| Latch-Up                                                             | JEDEC <i>JESD78</i>             | 3                       | Pass          |
| Electrostatic Discharge<br><i>Human Body Model</i>                   | ESDA/JEDEC <i>JS-001</i>        | 3/voltage               | Pass __3500V  |
| Electrostatic Discharge<br><i>Machine Model</i>                      | JEDEC <i>JESD22-A115</i>        | 3/voltage               | Pass ____100V |
| Electrostatic Discharge<br><i>Field-Induced Charged Device Model</i> | JEDEC <i>JESD22-C101</i>        | 3/voltage               | Pass __1250V  |

\*Preconditioned per JEDEC/IPC J-STD-020